

FDA33N25 N-Channel UniFETTM MOSFET 250 V, 33 A, 94 mΩ

Features

- $R_{DS(on)}$ = 88 m Ω (Typ.) @ V_{GS} = 10 V, I_D =16.5 A
- Low Gate Charge (Typ. 36 nC)
- Low C_{rss} (Typ. 35 pF)
- 100% Avalanche Tested
- RoHS Compliant

Applications

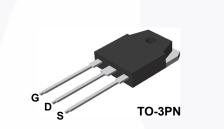
- PDP TV
- Uninterruptible Power Supply
- AC-DC Power Supply

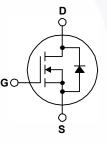
May 2014

FDA33N25 — N-Channel UniFETTM MOSFET

Description

UniFETTM MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter			FDA33N25	Unit	
V _{DSS}	Drain to Source Voltage			250	V	
V _{GSS}	Gate to Source Voltage			±30	V	
ID	Drain Current	- Continuous (T _C = 25 ^o C)		33	Α	
		- Continuous ($T_c = 100^{\circ}C$)	- Continuous ($T_c = 100^{\circ}C$)			
I _{DM}	Drain Current	- Pulsed	(Note 1)	132	Α	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)			918	mJ	
I _{AR}	Avalanche Current		(Note 1)	33	Α	
E _{AR}	Repetitive Avalanche Energy			24.6	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)			4.5	V/ns	
P _D	Power Dissipation	$(T_{\rm C} = 25^{\rm o}{\rm C})$		245	W	
		- Derate Above 25°C		1.96	W/ ^o C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C	

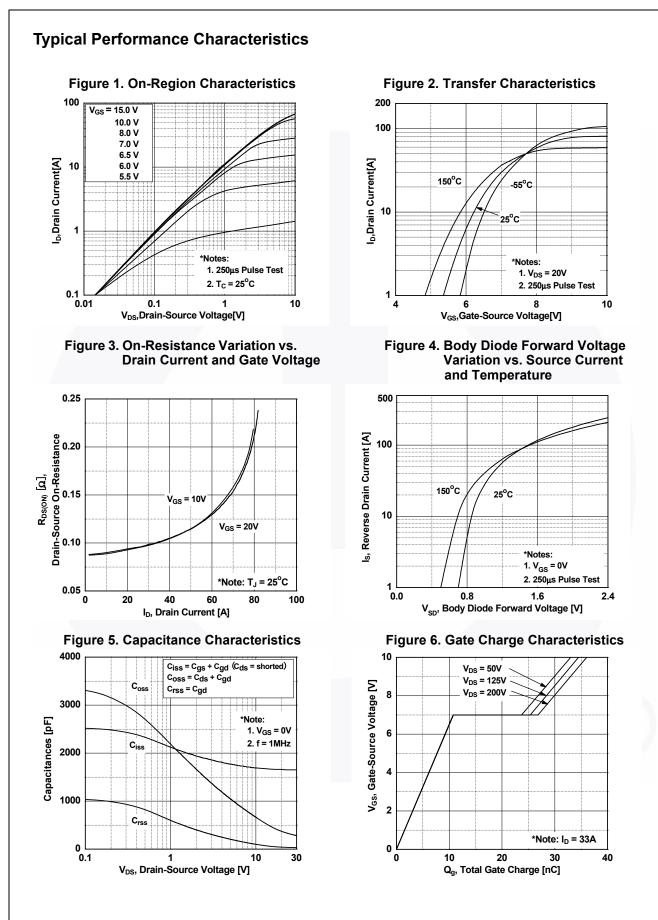
Thermal Characteristics

Symbol	Parameter	FDA33N25	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.51	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient, Max.	40	

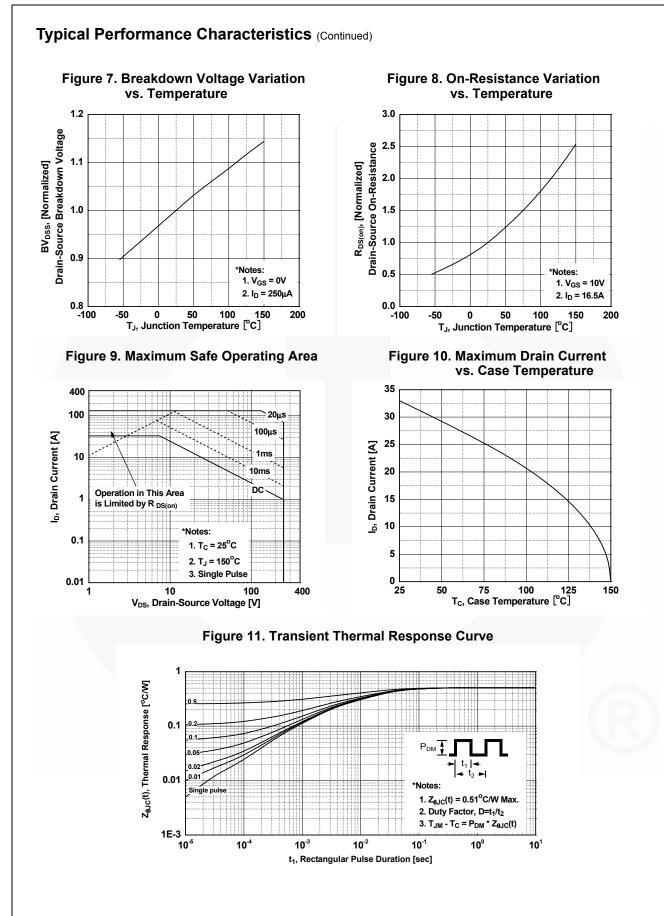
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Part Nu	mber	Top Mark	Package	Packing Method	Reel Size	e T	ape Width	Qu	antity
FDA33	N25	FDA33N25	TO-3PN	Tube	N/A		N/A	30 units	
Electrica	l Chara	cteristics T _c = 25°C u	inless othe	rwise noted.					
Symbol		Parameter		Test Conditio	ons	Min.	Тур.	Max.	Unit
Off Charac	teristics								
3V _{DSS}	Drain to Source Breakdown Voltage		I _D :	I _D = 250 μA, V _{GS} = 0 V, T _J = 25 ^o C			-	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature		I _D :	$I_D = 250 \ \mu$ A, Referenced to 25° C		-	0.34	-	V/ºC
DSS	Zero Gate Voltage Drain Current			$V_{DS} = 250 V, V_{GS} = 0 V$ $V_{DS} = 200 V, T_{C} = 125^{\circ}C$		-		1 10	μA
GSS	Gate to B	Gate to Body Leakage Current		_S = ±30 V, V _{DS} = 0 V		-	-	±100	nA
On Charac	teristics								
/ _{GS(th)}		eshold Voltage	Vc	_{iS} = V _{DS} , I _D = 250 μΑ		3.0	-	5.0	V
R _{DS(on)}		ain to Source On Resistance		$_{\rm is} = 10$ V, $I_{\rm D} = 16.5$ A		-	0.088	0.094	Ω
FS	Forward	Transconductance		_S = 20 V, I _D = 16.5 A		-	24.2	-	S
Dynamic C	haracter	istics		<u> </u>					
Siss	Input Cap					-	1655	2200	pF
Poss		apacitance		$_{\rm S}$ = 25 V, V _{GS} = 0 V,	-	-	315	420	pF
rss	-	Transfer Capacitance	f =	f = 1 MHz		-	35	55	pF
$Q_{g(tot)}$		e Charge at 10V	V	_S = 200 V, I _D = 33 A,		-	36	46.8	nC
λ _{gs}	Gate to S	ource Gate Charge		$_{\rm is} = 10 \text{ V}$	-	-	10.8	-	nC
Q _{gd}	Gate to D	rain "Miller" Charge			(Note 4)	-	16	-	nC
Switching	Characte	eristics							
d(on)	Turn-On I	Delay Time				-	33	76	ns
r	Turn-On I	Rise Time		V_{DD} = 125 V, I _D = 33 A, V _{GS} = 10 V, R _G = 25 Ω (Note 4)		-	142	293	ns
d(off)	Turn-Off	Delay Time	V _G			-	77	165	ns
f	Turn-Off I	all Time				•	68	146	ns
) rain-Sour	ce Diode	e Characteristics							
s	Maximum	Continuous Drain to Source	e Diode Fo	rward Current		-	-	33	Α
SM		Pulsed Drain to Source Dio					-	132	Α
/ _{SD}	Drain to S	Source Diode Forward Voltag	je V _G	V _{GS} = 0 V, I _{SD} = 33 A		-	-	1.4	V
rr	Reverse F	Recovery Time	_	V _{GS} = 0 V, I _{SD} = 33 A, dI _F /dt = 100 A/μs		-	256	-	ns
ک ^{رر}	Reverse F	Recovery Charge				-	2.3	-	μC
L = 1.35 mH, I _{AS} I _{SD} ≤ 33 A, di/dt	= 33 A, V _{DD} = ≤ 200 A/μs, V _D	nited by maximum junction temperatu 50 V, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. $_D \le BV_{DSS}$, starting $T_J = 25^{\circ}C$. ating temperature typical Characteris							

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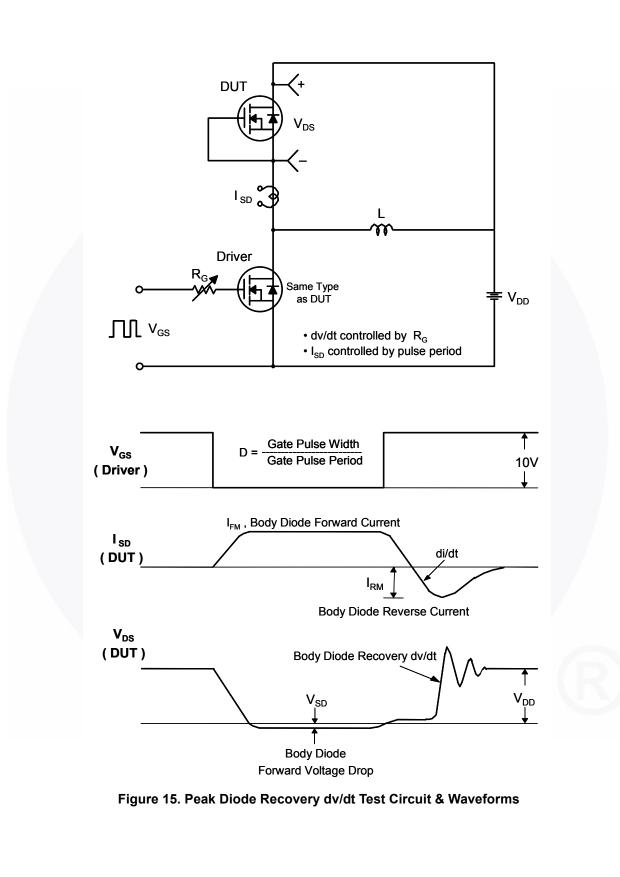
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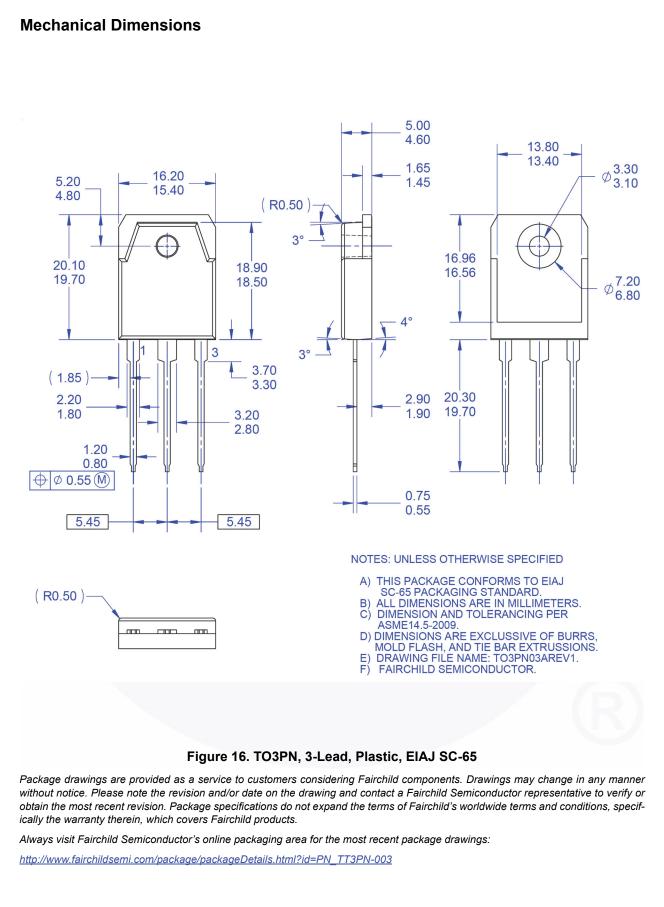
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 V_{GS} ξ א Q_g FV_{DS} Q_{gd} Q_{gs} • DUT I_G = const. Charge Figure 12. Gate Charge Test Circuit & Waveform R VDS V_{DS} 90% ο V_{DD} GS R_{G} 10% V_{GS} DUT V_{GS} ∏ 0 Figure 13. Resistive Switching Test Circuit & Waveforms L $E_{AS} = \frac{1}{2} L I_{AS}^2$ V_{DS} $\mathsf{BV}_{\mathsf{DSS}}$ ID o I_{AS} R_{G} ŧν_{DD} $I_{D}(t)$ V_{GS}] $V_{DS}(t)$ V_{DD} DUT Time t_p Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

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